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West Virginia, 1984-1986. SPIE: the International Society for Optical Engineering, March 17 62nd Annual Forum Proceedings, Volume 3, pp. 1531-1535, May 9
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Patent us9036209 - system for distributing and

The system provides for controlling color reproduction of input color image in a network having nodes (or sites). The system distributes the input color image data

Sci publications

Data, In Proceedings of the Third International 2014 IEEE Int. Conf. Engineering and Biology Society in infants, In Proceedings of SPIE

Patent wo2003102853a1 - selection of wavelengths

Specific wavelengths to use in optical metrology of an integrated circuit can be selected using one or more selection criteria and termination criteria.

Integrated circuit metrology with confocal

Integrated circuit metrology with confocal optical microscopy and indeed may be theoretically predicted: INTEGRATED CIRCUIT METROLOGY 309 (a) R=1 R=O (b)

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10-11 May 1984 Arlington, Virginia Naval Metrology Engineering Center 3. Electro-Optical Metrology: 10 (12%) 4.

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Arlington, Virginia, USA (2011) Proceedings of International Nano-Optoelectronics (International Society for Optical Engineering), San Jose, USA

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Littler, christopher leslie (faculty profile)

entitled "A Three-Dimensional Ferroelectric Integrated Circuit and Society Symposium Proceedings, on Optical Engineering, Dallas, Texas, May

Conference paper/presentations - texas tech

and High Voltage Conference, Proceedings of the 2008 27-31 May 2008 Society for Engineering Arlington Gateway Hotel, Arlington, Virginia,

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Arlington, Virginia, (International Society for Optical Engineering), San for single and coupled integrated optical waveguides. IEE Proceedings

Curriculum vitae - southern methodist university

Adaptive Fuzzy Process Control of Integrated Circuit Wire Bonding, May Arlington, Virginia, Proceedings of World Congress on Neural Networks, San

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Patent us7710560 - system for distributing and

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(May 27-July 3) at the Virginia Tech of new circuit design platform for engineering at VTRC Arlington. Virginia Tech emphasizes its

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with up to 9 million transistors per mm². Integrated circuits are used in virtually all electronic Electronic Components in Washington, D.C. on 7 May

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Massood tabib-azar

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Optical Engineering; Information for Authors; Proceedings of SPIE Volume 0480 Integrated Circuit Metrology II. Editor(s): Diana

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